

Search Notes

Application/Control No.

10/563,002

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

FREDERIKSEN ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	10	1/11/2008	HN
330	207A	1/11/2008	HN
330	251	1/11/2008	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PGPUB		1/11/2008	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	1/9/2008	HN